

<b>Notice of References Cited</b>	Application/Control No. 09/499,693	Applicant(s)/Patent Under Reexamination LEE ET AL.	
	Examiner Gregory W. Mitchell	Art Unit 1617	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
✓	A	US-3,966,960	06-1976	Ellenbogen et al.	514/570
✓	B	US-2,353,571	07-1944	KRAYBILL HENRY R; et. al.	554/83
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	EP 0 435 683	07-1991	EPO	Kobayashi et al.	---
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	P					
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	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Aldrich Catalog Handbook of Fine Chemicals 1994, 866-867, 1075.
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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